

CLAIMSWhat Is Claimed Is:

- 1 1. In a spectral ellipsometer having a source of multi-wavelength light, an
2 optical system for directing the light, and a detecting optical system for receiving light
3 after contact with a sample surface, the improvement comprising:
4 an optical element for receiving the multi-wavelength light directed from
5 the optical system and focusing the multiple wavelength light onto a single spot on the
6 sample surface.
- 1 2. The spectral ellipsometer of Claim 1 wherein the optical element is a
2 spherical prism.
- 1 3. The spectral ellipsometer of Claim 1 wherein the optical element is a
2 polarizing prism with at least one curved surface for transmitting the multi-wavelength
3 light.
- 1 4. In a spectral ellipsometer, which includes a light incidence optical system
2 for achieving spot incidence of polarization light of multi-wavelengths onto a sample
3 surface and a detecting optical system for outputting information concerning the sample
4 surface based on an amount of change in elliptical polarization reflected by the sample
5 surface, the improvement comprising a prism polarizer employed in the light incidence
6 optical system with a curved light-incident surface and a curved light-outgoing surface
7 that is orthogonal with respect to a progressing direction of the respective direction of
8 incident and outgoing light.

